

## CA3060A/...

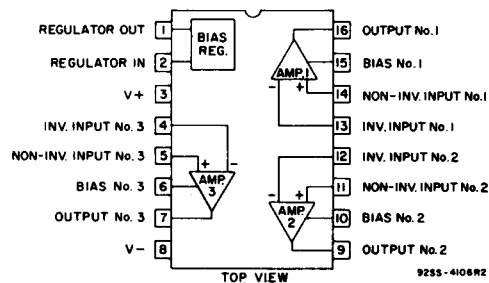
Operational Transconductance  
Amplifier Arrays

The CA3060 Slash (/) Series type is supplied in the 16-lead dual-in-line ceramic package (D suffix).

TABLE A. POST BURN-IN, FINAL ELECTRICAL AND GROUP A SAMPLING TESTS

CHARACTERISTIC	SYMBOL	TEST CONDITIONS	LIMITS						UNITS
			MIN.			MAX.			
			-55° C	+25° C	+125° C	-55° C	+25° C	+125° C	
Input Offset Voltage	$V_{IO}$	$V+ = +15\text{ V}, V- = -15\text{ V}$	-6	-5	-6	+6	+5	+6	mV
Input Bias Current	$I_{IB}$	$I_{ABC} = 100\ \mu\text{A}$	—	—	—	10000	5000	10000	nA
Input Offset Current	$I_{IO}$		-2000	-1000	-2000	2000	1000	2000	nA
Input Offset Voltage Sensitivity	$\Delta V_{IO}/\Delta V+$		-150	-150	-150	+150	+150	+150	$\mu\text{V}/\text{V}$
	$\Delta V_{IO}/\Delta V-$		-150	-150	-150	+150	+150	+150	$\mu\text{V}/\text{V}$
Peak Output Voltage	$V_{OM+}$		12	12	12	15	15	15	V
Peak Output Voltage	$V_{OM-}$		-15	-15	-15	-12	-12	-12	V
Amplifier Supply Current	$I_A$		—	—	—	1500	1200	1500	$\mu\text{A}$
<b>Zener Bias Regulator</b>									
Zener Voltage	$V_Z$	$I_Z = 100\ \mu\text{A}$	5.9	6.2	5.9	8.2	7.9	8.2	V
Zener Voltage	$V_Z$	$I_Z = 1\ \text{mA}$	5.9	6.3	6.0	8.2	8.0	8.2	V

\* (each ampl.)



Functional block diagram.

**TABLE B. DELTA LIMITS** at  $T_A = 25^\circ\text{C}$ ,  $V^+ = +15\text{ V}$ ,  $V^- = -15\text{ V}$ ,  $I_{ABC} = 100\ \mu\text{A}$  (1 only)

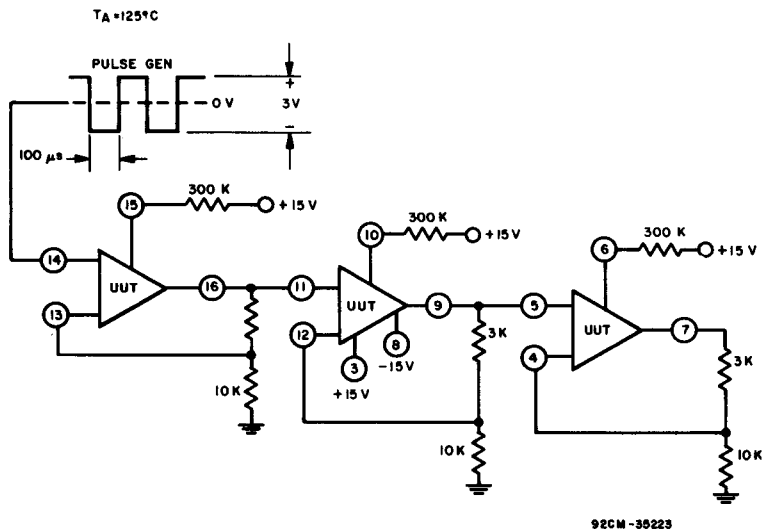
CHARACTERISTIC		LIMITS	UNITS
		MAX. $\Delta$	
Input Offset Voltage	$V_{io}$	$\pm 0.15$	mV
Input Offset Current	$i_{io}$	$\pm 50$	nA
Input Bias Current	$i_{ib}$	$\pm 250$	nA

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**TABLE C. GROUPS C AND D END-POINT TESTS** at  $T_A = 25^\circ\text{C}$ ,  $V^+ = +15\text{ V}$ ,  $V^- = -15\text{ V}$ ,  $I_{ABC} = 100\ \mu\text{A}$ 

CHARACTERISTIC		LIMITS		UNITS
		MIN.	MAX.	
Input Offset Voltage	$V_{io}$	-10	+10	mV
Input Offset Current	$i_{io}$	-2000	+2000	nA
Input Bias Current	$i_{ib}$	—	9000	nA
Peak Output Voltage	$V_{om+}$	10	15	V
Peak Output Voltage	$V_{om-}$	-15	-10	V
Amplifier Supply Current (each amp)	$I_A$	—	1500	$\mu\text{A}$

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*Burn-in and operating life-test circuit.*